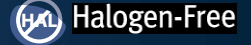


# EPC2021 – 80 V (D-S) Enhancement Mode Power Transistor

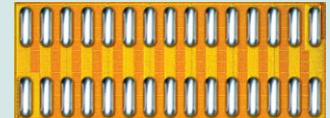
 $V_{DS}, 80\text{ V}$ 
 $R_{DS(on)}, 2.2\text{ m}\Omega$ 
 $I_D, 90\text{ A}$ 


Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low  $R_{DS(on)}$ , while its lateral device structure and majority carrier diode provide exceptionally low  $Q_G$  and zero  $Q_{RR}$ . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

Maximum Ratings			
PARAMETER		VALUE	UNIT
$V_{DS}$	Drain-to-Source Voltage (Continuous)	80	V
$I_D$	Continuous ( $T_A = 25^\circ\text{C}$ )	90	A
	Pulsed ( $25^\circ\text{C}$ , $T_{PULSE} = 300\text{ }\mu\text{s}$ )	390	
$V_{GS}$	Gate-to-Source Voltage	5	V
	Gate-to-Source Voltage	-4	
$T_J$	Operating Temperature	-40 to 150	$^\circ\text{C}$
$T_{STG}$	Storage Temperature	-40 to 150	

Thermal Characteristics			
PARAMETER		TYP	UNIT
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.4	$^\circ\text{C}/\text{W}$
$R_{\theta JB}$	Thermal Resistance, Junction-to-Board	1.1	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)	42	

Note 1:  $R_{\theta JA}$  is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See [https://epc-co.com/epc/documents/product-training/Appnote\\_Thermal\\_Performance\\_of\\_eGaN\\_FETs.pdf](https://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf) for details.



**EPC2021** eGaN® FETs are supplied only in passivated die form with solder bars. Die Size: 6.05 mm x 2.3 mm

## Applications

- High Frequency DC-DC Conversion
- Motor Drive
- Industrial Automation
- Synchronous Rectification
- Inrush Protection
- Class-D Audio

## Benefits

- Ultra High Efficiency
- No Reverse Recovery
- Ultra Low  $Q_G$
- Small Footprint

Static Characteristics ( $T_J = 25^\circ\text{C}$ unless otherwise stated)						
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$BV_{DSS}$	Drain-to-Source Voltage	$V_{GS} = 0\text{ V}$ , $I_D = 500\text{ }\mu\text{A}$	80			V
$I_{DSS}$	Drain-Source Leakage	$V_{GS} = 0\text{ V}$ , $V_{DS} = 80\text{ V}$		20	200	$\mu\text{A}$
$I_{GSS}$	Gate-to-Source Forward Leakage	$V_{GS} = 5\text{ V}$ , $T_J = 25^\circ\text{C}$		0.02	4	mA
	Gate-to-Source Forward Leakage <sup>#</sup>	$V_{GS} = 5\text{ V}$ , $T_J = 125^\circ\text{C}$		0.1	9	mA
	Gate-to-Source Reverse Leakage	$V_{GS} = -4\text{ V}$		20	200	$\mu\text{A}$
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 13\text{ mA}$	0.7	1.2	2.5	V
$R_{DS(on)}$	Drain-Source On Resistance	$V_{GS} = 5\text{ V}$ , $I_D = 29\text{ A}$		1.8	2.2	m $\Omega$
$V_{SD}$	Source-Drain Forward Voltage	$I_S = 0.5\text{ A}$ , $V_{GS} = 0\text{ V}$		1.5		V

All measurements were done with substrate connected to source.

<sup>#</sup> Defined by design. Not subject to production test.

Dynamic Characteristics ( $T_J = 25^\circ\text{C}$  unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$C_{ISS}$	Input Capacitance <sup>#</sup>	$V_{DS} = 40\text{ V}, V_{GS} = 0\text{ V}$		1610	1940	pF
$C_{RSS}$	Reverse Transfer Capacitance			15		
$C_{OSS}$	Output Capacitance <sup>#</sup>			1100	1650	
$C_{OSS(ER)}$	Effective Output Capacitance, Energy Related (Note 2)	$V_{DS} = 0\text{ to }40\text{ V}, V_{GS} = 0\text{ V}$		1450		
$C_{OSS(TR)}$	Effective Output Capacitance, Time Related (Note 3)			1790		
$R_G$	Gate Resistance			0.3		$\Omega$
$Q_G$	Total Gate Charge <sup>#</sup>	$V_{DS} = 40\text{ V}, V_{GS} = 5\text{ V}, I_D = 29\text{ A}$		15	19	nC
$Q_{GS}$	Gate-to-Source Charge	$V_{DS} = 40\text{ V}, I_D = 29\text{ A}$		4.1		
$Q_{GD}$	Gate-to-Drain Charge			3		
$Q_{G(TH)}$	Gate Charge at Threshold			2.7		
$Q_{OSS}$	Output Charge <sup>#</sup>	$V_{DS} = 40\text{ V}, V_{GS} = 0\text{ V}$		72	108	
$Q_{RR}$	Source-Drain Recovery Charge			0		

All measurements were done with substrate connected to source.

<sup>#</sup> Defined by design. Not subject to production test.

Note 2:  $C_{OSS(ER)}$  is a fixed capacitance that gives the same stored energy as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 50%  $BV_{DSS}$ .

Note 3:  $C_{OSS(TR)}$  is a fixed capacitance that gives the same charging time as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 50%  $BV_{DSS}$ .

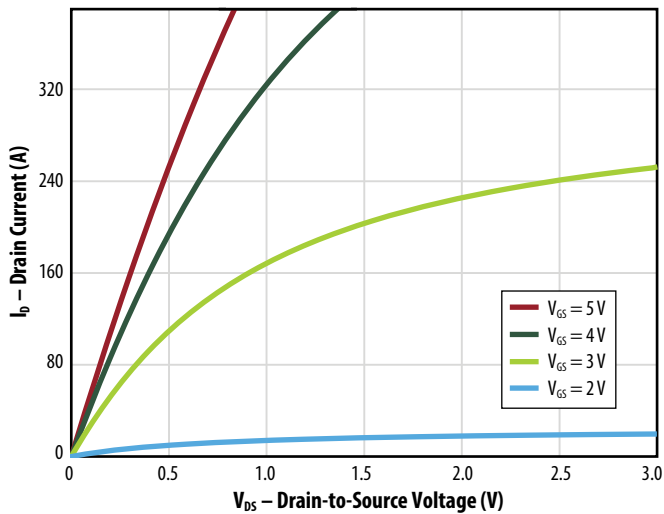
Figure 1: Typical Output Characteristics at  $25^\circ\text{C}$ 

Figure 2: Transfer Characteristics

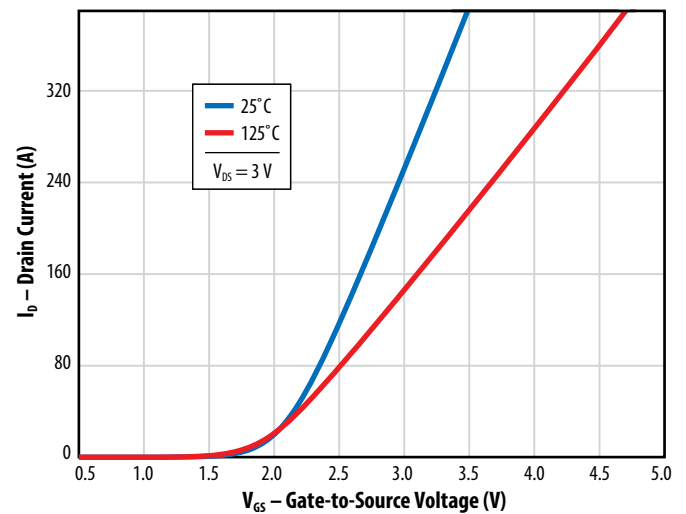
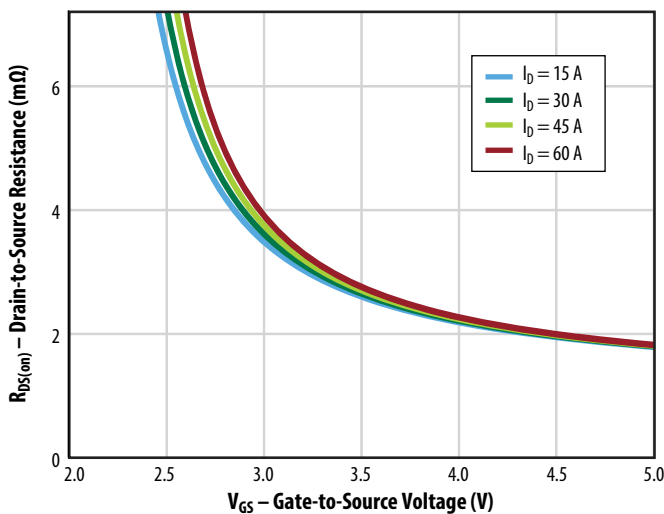
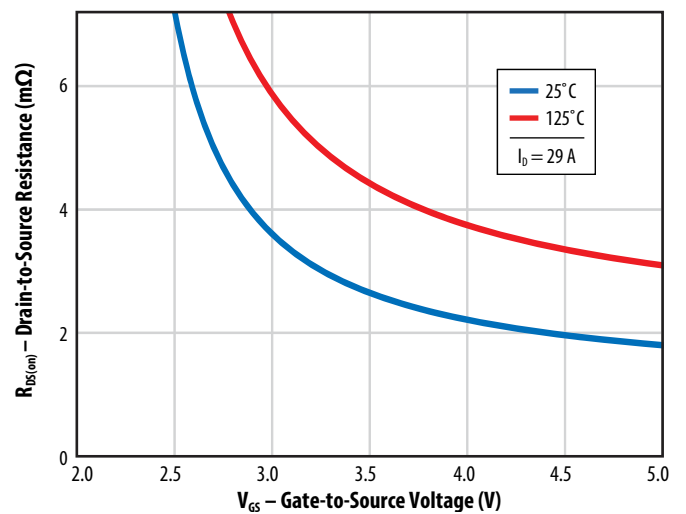
Figure 3:  $R_{DS(on)}$  vs.  $V_{GS}$  for Various Drain CurrentsFigure 4:  $R_{DS(on)}$  vs.  $V_{GS}$  for Various Temperatures

Figure 5a: Capacitance (Linear Scale)

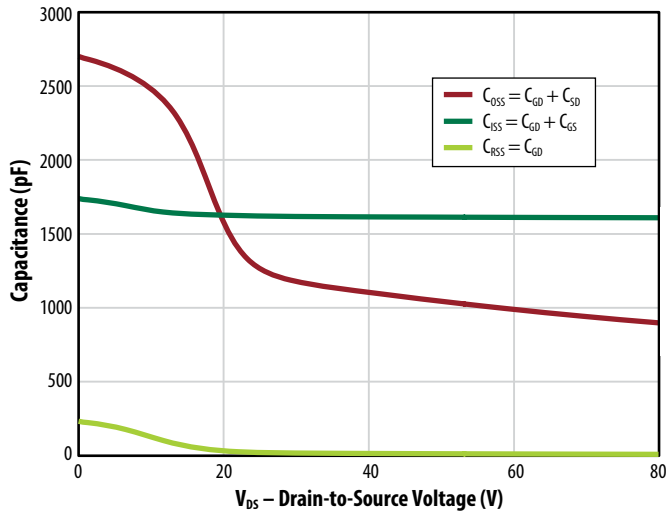


Figure 5b: Capacitance (Log Scale)

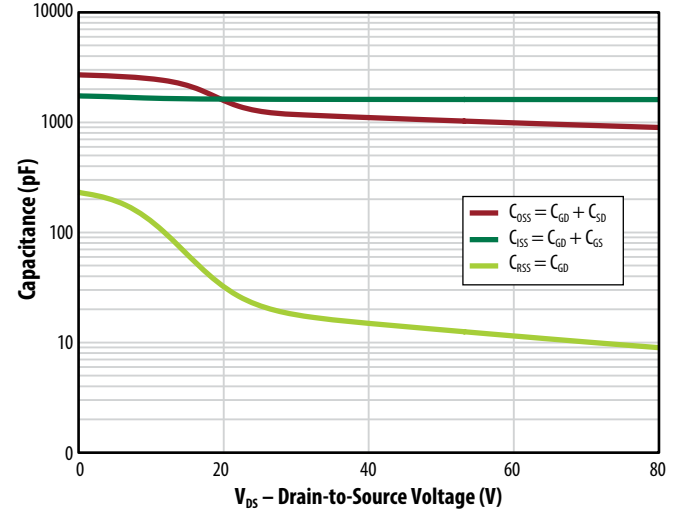
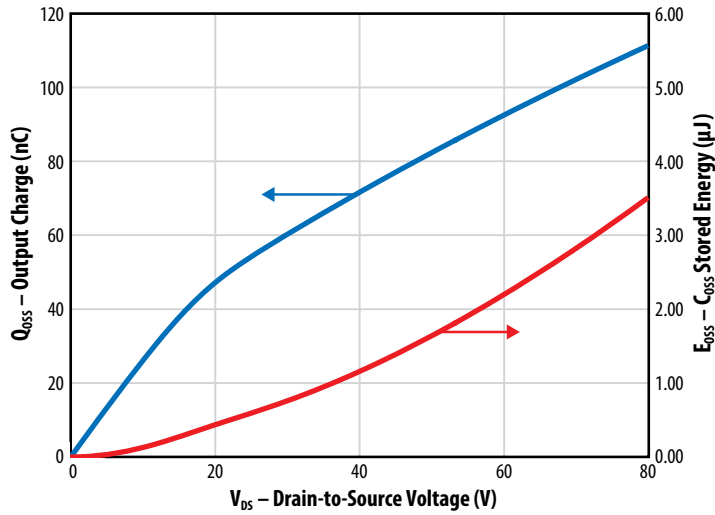
Figure 6: Output Charge and  $C_{OSS}$  Stored Energy

Figure 7: Gate Charge

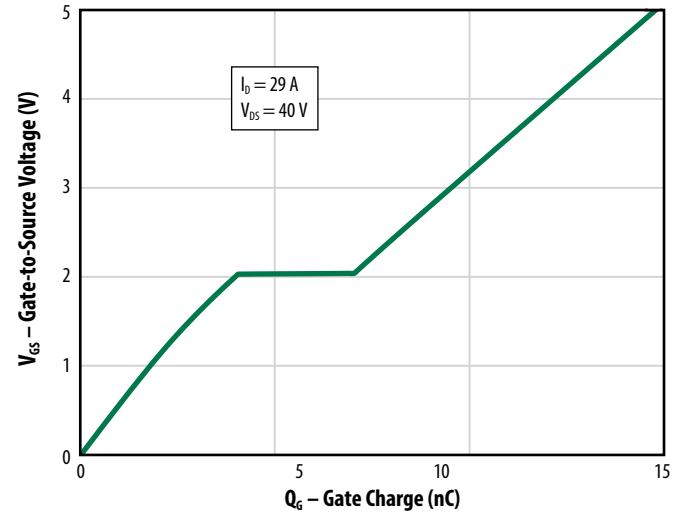


Figure 8: Reverse Drain-Source Characteristics

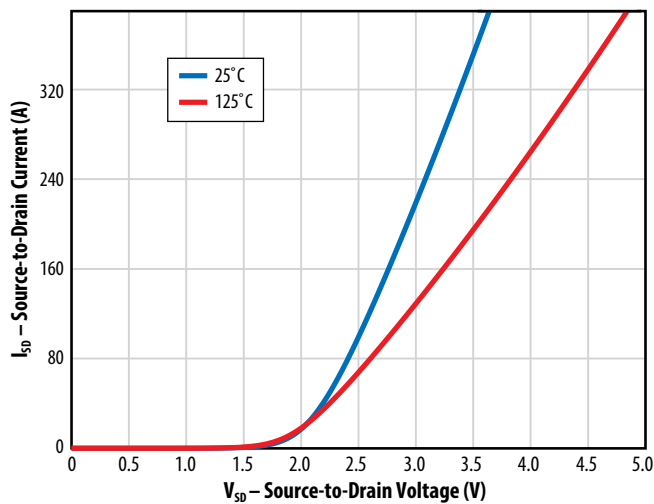


Figure 9: Normalized On-State Resistance vs. Temperature

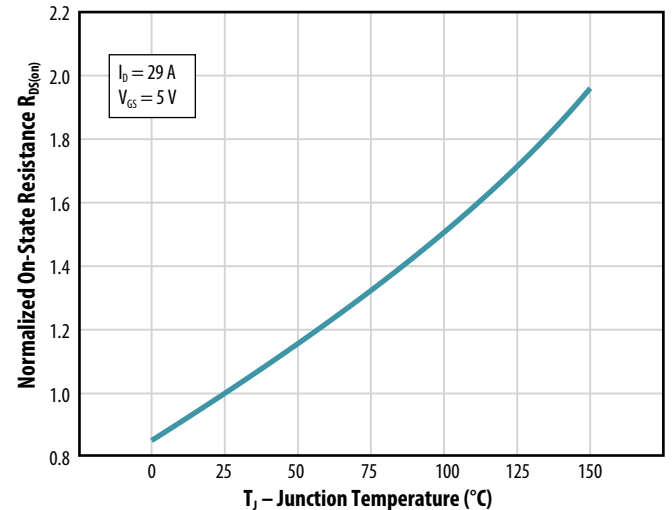


Figure 10: Normalized Threshold Voltage vs. Temperature

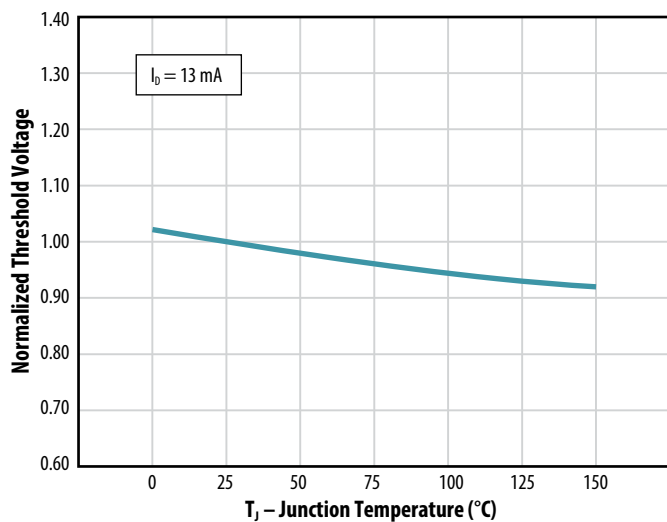


Figure 11: Safe Operating Area

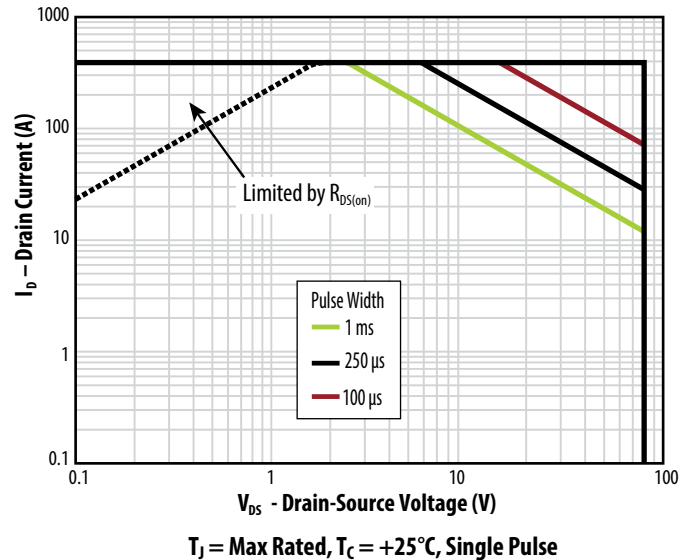
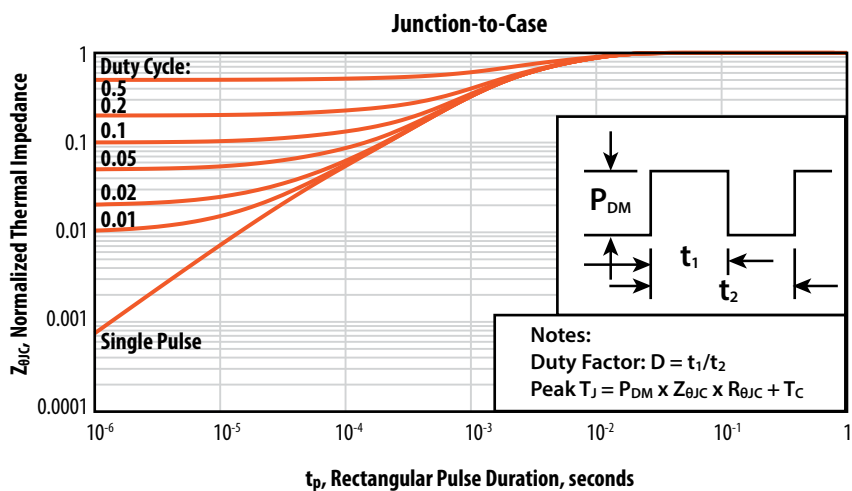
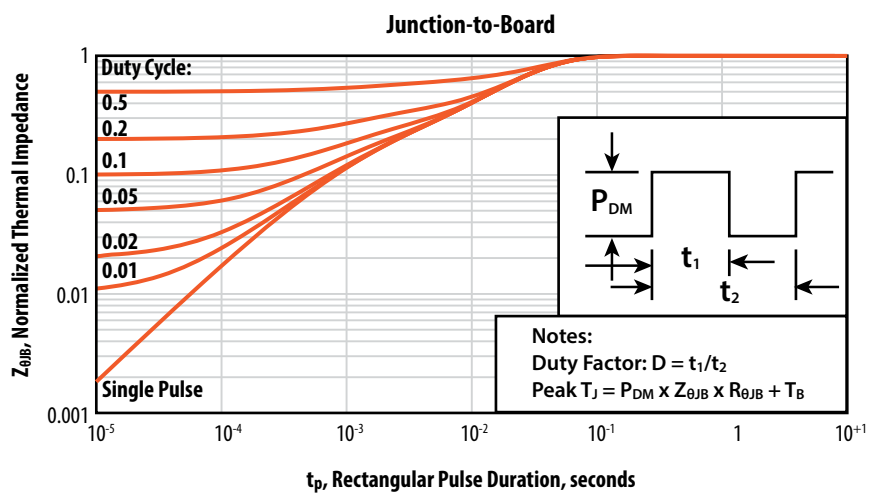
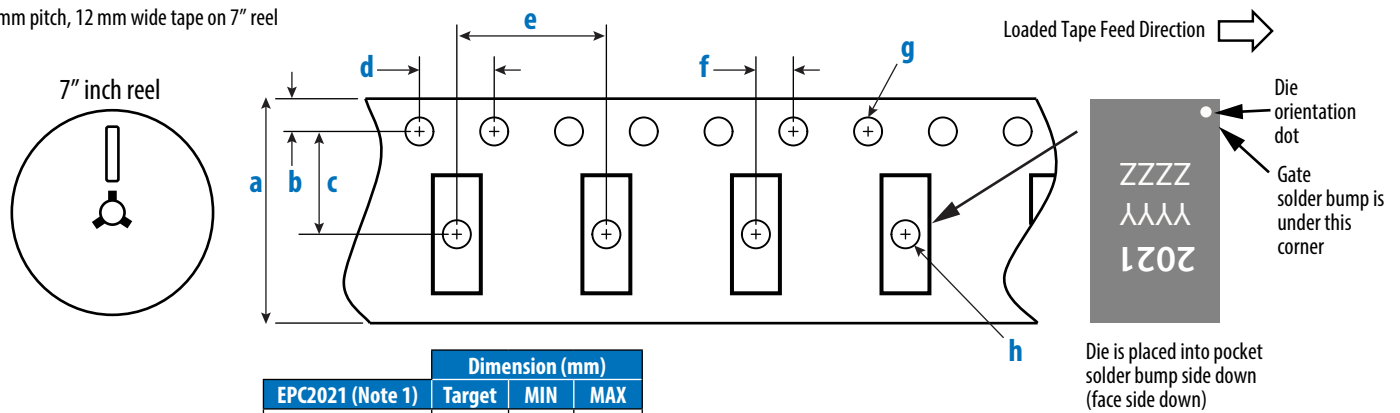


Figure 12: Transient Thermal Response Curves



## TAPE AND REEL CONFIGURATION

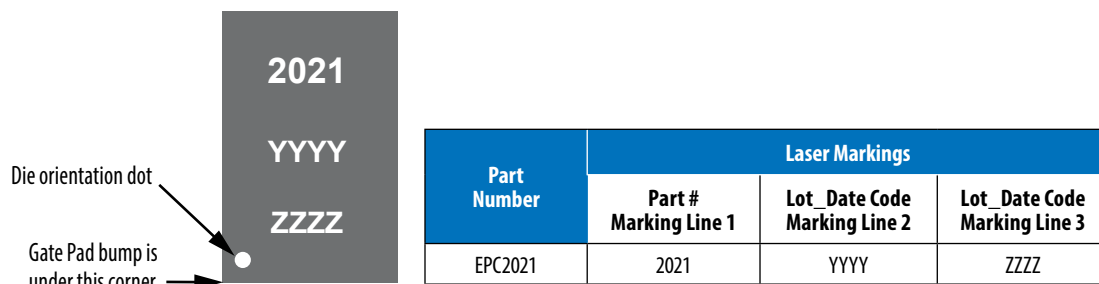
8 mm pitch, 12 mm wide tape on 7" reel



Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/ JEDEC industry standard.

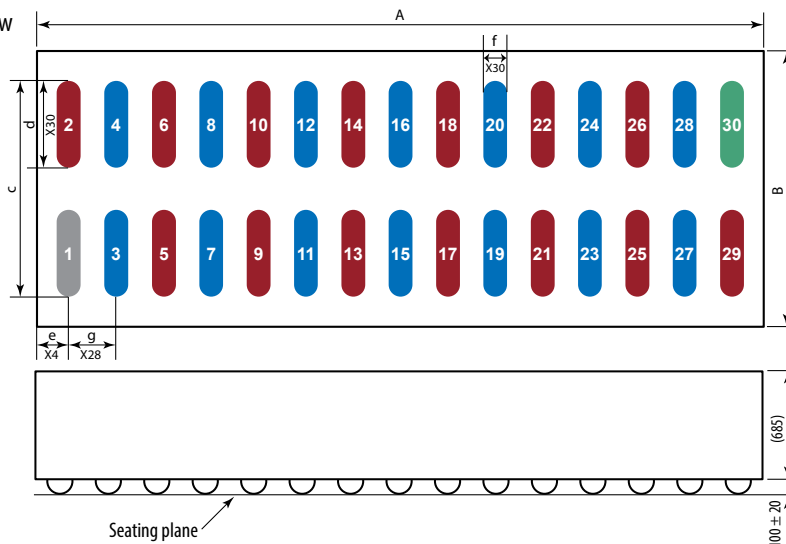
Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

## DIE MARKINGS



## DIE OUTLINE

Solder Bump View



DIM	Micrometers		
	MIN	Nominal	MAX
A	6020	6050	6080
B	2270	2300	2330
c	2047	2050	2053
d	717	720	723
e	210	225	240
f	195	200	205
g	400	400	400

Pad 1 is Gate;

Pads 2, 5, 6, 9, 10, 13, 14, 17, 18, 21, 22, 25, 26, 29 are Source;

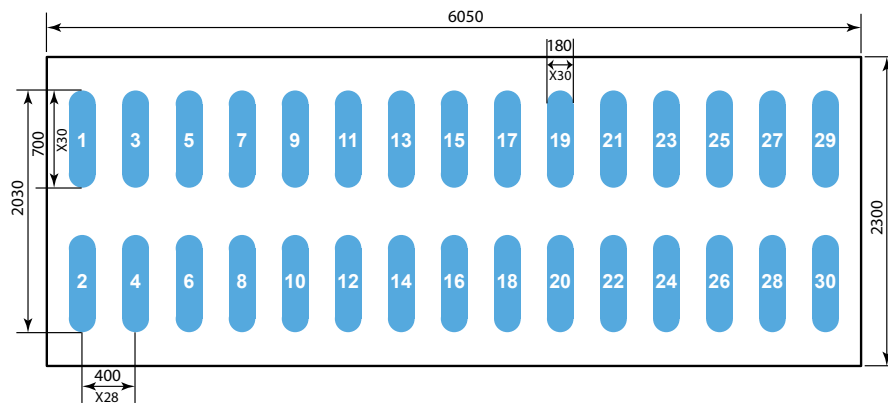
Pads 3, 4, 7, 8, 11, 12, 15, 16, 19, 20, 23, 24, 27, 28 are Drain;

Pad 30 is Substrate.\*

\*Substrate pin should be connected to Source

## RECOMMENDED LAND PATTERN

(units in  $\mu\text{m}$ )



Land pattern is solder mask defined  
Solder mask opening is  $180\ \mu\text{m}$   
It is recommended to have on-Cu trace PCB vias

Pad 1 is Gate;

Pads 2, 5, 6, 9, 10, 13, 14, 17, 18, 21, 22, 25, 26, 29 are Source;

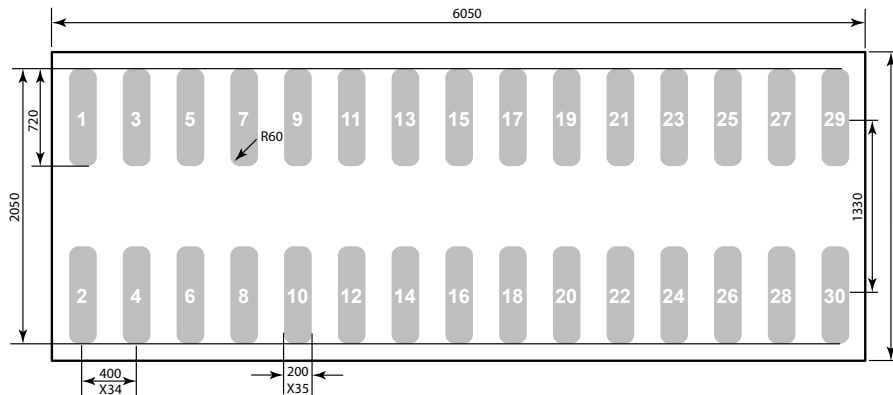
Pads 3, 4, 7, 8, 11, 12, 15, 16, 19, 20, 23, 24, 27, 28 are Drain;

Pad 30 is Substrate.\*

\*Substrate pin should be connected to Source

## RECOMMENDED STENCIL DRAWING

(units in  $\mu\text{m}$ )



Recommended stencil should be 4 mil ( $100\ \mu\text{m}$ ) thick, must be laser cut, openings per drawing.

Intended for use with SAC305 Type 3 solder, reference 88.5% metals content.

Additional assembly resources available at  
<https://epc-co.com/epc/DesignSupport/AssemblyBasics.aspx>

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**Note:** Datasheet is applicable for devices with date code of 1918 and later. For older date code devices please contact EPC for data sheet

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change without notice.  
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